## LITERATURE REVIEW

SL. NO	TITLE	YEAR	TECHNOLOGY	DRAWBACKS	LIN K
01	Advancing cryptographic security: a novel hybrid AES-RSA model with byte-level tokenization	Apr 16, 2024	<ul> <li>byte-level Byte-Pair Encoding (BPE) tokenizer.</li> <li>RSA algorithm</li> <li>Advanced Encryption Standard (AES).</li> </ul>	<ul> <li>Increased         Computational         Overhead</li> <li>Complexity in Key         Management</li> <li>Potential         Vulnerabilities in         Tokenization</li> </ul>	[A]
02	Design and Implementation of Memory Controller for Byte Access from Data Memory for SoC's Devices	July, 2024	<ul> <li>System-on-Chip (SoC)         Architecture.</li> <li>Advanced eXtensible         Interface (AXI).</li> <li>Verilog and         SystemVerilog UVM         (Universal         Verification         Methodology).</li> </ul>	<ul> <li>Limited Scalability in Multi-Processor Environments.</li> <li>Limited Flexibility in Dynamic Environments</li> <li>Verification and Validation Challenges</li> </ul>	[B]
03	Optimizing Systems for Byte-Addressable NVM by Reducing Bit Flipping	Februar y, 2019	<ul> <li>Phase Change Memory (PCM).</li> <li>XOR Linked Lists.</li> <li>XOR Hash Tables.</li> <li>XOR Red-Black Tree.</li> </ul>	<ul> <li>PCM Write Endurance Power Consumption</li> <li>Memory Allocation Overhead.</li> <li>XOR Hash Tables, Complexity</li> </ul>	

04	20nm High-density single-port and dual- port SRAMa with worldline-voltage- adjustments system for read/write assists	06 March 2014	<ul> <li>Wordline-Voltage- Adjustment System</li> <li>On-Chip Voltage Regulator</li> <li>Temperature Monitoring and Control</li> <li>Temperature and Process Variation- Based Adjustmen</li> </ul>	<ul> <li>Increased Complexity</li> <li>Write/Read Disturb         Issues in DP-SRAM</li> <li>Timing         Considerations</li> </ul>	D
05	A 45-nm Single-port and Dual-port SRAM family with Robust Read/Write Stabilizing Circuitry under DVFS Environment.	01 August 2008	<ul> <li>Improved Wordline Suppression Circuitry</li> <li>Negative Bitline Technique.</li> <li>45nm CMOS Technology</li> </ul>	<ul> <li>Process Variation         Sensitivity</li> <li>Complexity in         Negative Bitline         Implementation</li> </ul>	E